



2872

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Appl. No. : 10/085,507 Confirmation No. 8689
Applicant : John W. Orcutt
Filed : 02/26/2002
TC/A.U. : 2872
Examiner : Shafer, Ricky D.

Docket No. : TI-32675
Customer No. : 23494

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INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97 & 1.98

Commissioner for Patents
P. O. Box 1450
Alexandria, VA 22313-1450

MAILING CERTIFICATE UNDER 37 C.F.R. § 1.8(a)
I hereby certify that the above correspondence is being deposited with the U.S. Postal Service as First Class Mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.


William B. Kempf Date 10/7/03

Dear Sir:

In the matter of the above identified application, Applicants are submitting herewith copies of documents listed in the attached form equivalent to Form PTO-1449 for the Examiner's consideration.

In accordance with 37 CFR 1.97 (c), this Information Disclosure Statement is being submitted before the mailing date of a Final Action or a Notice of Allowance and is accompanied by the following certification specified in 37 CFR 1.97 (e).

On information and belief, I hereby certify that each item of information contained in this Information Disclosure Statement was cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.

Pursuant to 37 CFR 1.97 (d), Applicants respectfully petition that this Information Disclosure Statement be considered by the Examiner.

Please charge any shortage in the fees due in connection with the filing of this paper, including extension of time fees, to the Deposit Account No. 20-0668 of Texas Instruments Incorporated, and please credit any excess fees to such Deposit Account.

This form is submitted in triplicate.

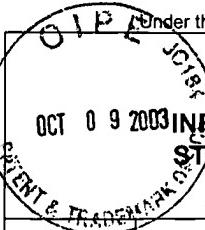
Respectfully submitted,

Texas Instruments Incorporated

By


William B. Kempler
Senior Corporate Patent Counsel
Reg. No. 28,228
Tel.: (972) 917-5452

Please type a plus sign (+) inside this box



Substitute for Form 1449A/PTO

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(use as many sheets as necessary)

Sheet

1

of

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Complete If Known

Application Number	10/085,507
Filing Date	02/26/2002
First Named Inventor	John W. Orcutt
Group Art Unit	2872
Examiner Name	Shafer, Ricky D.

Attorney Docket No.

TI-32675

U.S. PATENT DOCUMENTS

Exam. Initials*	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Doc.	Date of Pub. of Cited Doc. (mm-dd-yyyy)	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code ² (if known)			
AA	6,094,293			Yokoyama, et al	07/25/2000	
AB						
AC						
AD						
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FOREIGN PATENT DOCUMENTS

Exam. Initials*	Cite No. ¹	Foreign Patent Document			Name of Patentee or Applicant of Cited Doc.	Date of Pub. of Cited Doc. (mm-dd-yyyy)	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		Office ³	Number ⁴	Kind Code ² (if known)				
BA	EP	0 962 796 A2			Congdon, et al	12/08/1999		
BB	DE	42 35 593 A1			Reicheneder	10/21/1993		
BC								
BD								
BE								
BF								
BG								
BH								

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS

Exam. Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
CA	KIM, "A laser-based 2-dimensional angular deflection measurement system for tilting microplates", Sensors Actuators, 86 (2000), pages 141-147, Elsevier, BNSDOCID: <XP 4224542A 1 >.		
CB	CHUNG, "Measurements of a fabricated micro mirror using a lateral-effect position-sensitive photodiode", Electronics, IEEE Inc. New York, U.S., vol. 45, no. 6, 1 December 1998 (1998-12-01), pages 861-865, XP000789096, ISSN: 0278-0046, abstract, pages 861-865.		
CC	TUANTRANONT, "Smart phase-only micromirror array fabricated by standard CMOS process", Proceedings IEEE Thirteenth Annual International Conference on Micro Electro Mechanical Systems, Miyazaki, Japan, 23-27 Jan. 2000, pages 455-460.		
CD			
CE			
CF			
CG			
CH			

Examiner Signature	Date Considered
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

US and Foreign Patent Documents: ¹Unique citation designation number. ²See attached Kinds of U.S. Patent Documents. ³Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶Applicant is to place a check mark here if English language Translation is attached.

Other Prior Art/Non-Patent Literature Documents: ¹Unique citation designation number. ²Applicant is to place a check mark here if English Translation is attached.



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Europäisches
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Département à
La Haye
Division de la
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GRANDE BRETAGNE

Datum/Date
08.07.03

Zeichen/Ref./Réf. TI-32675 EP	Anmeldung Nr./Application No./Demande n°/Patent Nr. /Patent No./Brevet n°. 02100191.2-2217-
Anmelder/Applicant/Demandeur/Patentinhaber/Propriétaire/Titulaire Texas Instruments Incorporated	

COMMUNICATION

The European Patent Office herewith transmits as an enclosure the European search report for the above-mentioned European patent application.

If applicable, copies of the documents cited in the European search report are attached.

Additional set(s) of copies of the documents cited in the European search report is (are) enclosed as well.

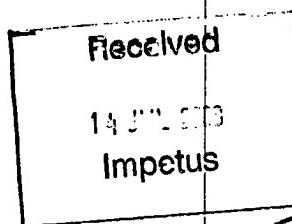
The following specifications given by the applicant have been approved by the Search Division:

abstract title

The abstract was modified by the Search Division and the definitive text is attached to this communication.

The following figure will be published together with the abstract:

1



REFUND OF THE SEARCH FEE

If applicable under Article 10 Rules relating to fees, a separate communication from the Receiving Section on the refund of the search fee will be sent later.



**European Patent
Office**

EUROPEAN SEARCH REPORT

Application Number

DOCUMENTS CONSIDERED TO BE RELEVANT			CLASSIFICATION OF THE APPLICATION (Int.Cl.7)
Category	Citation of document with indication, where appropriate, of relevant passages	Relevant to claim	
D, X	EP 0 962 796 A (TEXAS INSTRUMENTS INC) 8 December 1999 (1999-12-08) * column 6, paragraph 18 - paragraph 19 *	1-4, 7, 8, 11	G02B26/08
Y	* column 7, paragraph 24 - column 8, paragraph 27 * * column 8, paragraph 31 - column 9, paragraph 33; figures 1,3,7,7A *	1,5,6	
Y	US 6 094 293 A (OTA HITOSHI ET AL) 25 July 2000 (2000-07-25) * column 2, line 12 - line 17 * * column 6, line 43 - column 7, line 42 * * column 12, line 9 - line 26; figures 1,12 *	1,5,6	
X	DE 42 35 593 A (TECHNOLOGIE PLATTFORM THUERING) 21 October 1993 (1993-10-21) * abstract * * column 2, line 19 - line 35; figures 1,2 *	1,2,7, 9-11	
X	KIM H ET AL: "A laser-based 2-dimesional angular deflection measurement system for tilting microplates" SENSORS AND ACTUATORS A, ELSEVIER SEQUOIA S.A., LAUSANNE, CH, vol. 86, no. 1-2, 30 October 2000 (2000-10-30), pages 141-147, XP004224542 ISSN: 0924-4247 * abstract * * page 141 " 1.Introduction" * * pages 142-143 "3.Measurement Systems" * ---	1,2,5-7, 9-11	G02B
The present search report has been drawn up for all claims			
Place of search	Date of completion of the search	Examiner	
MUNICH	30 June 2003	Besser, V	
CATEGORY OF CITED DOCUMENTS			
X : particularly relevant if taken alone	T : theory or principle underlying the invention		
Y : particularly relevant if combined with another document of the same category	E : earlier patent document, but published on, or after the filing date		
A : technological background	D : document cited in the application		
O : non-written disclosure	L : document cited for other reasons		
P : intermediate document	& : member of the same patent family, corresponding document		



European Patent
Office

EUROPEAN SEARCH REPORT

Application Number
EP 02 10 0191

DOCUMENTS CONSIDERED TO BE RELEVANT

Category	Citation of document with indication, where appropriate, of relevant passages	Relevant to claim	CLASSIFICATION OF THE APPLICATION (Int.Cl.7)												
X	<p>CHUNG S-W ET AL: "MEASUREMENTS OF A FABRICATED MICRO MIRROR USING A LATERAL-EFFECT POSITION-SENSITIVE PHOTODIODE" IEEE TRANSACTIONS ON INDUSTRIAL ELECTRONICS, IEEE INC. NEW YORK, US, vol. 45, no. 6, 1 December 1998 (1998-12-01), pages 861-865, XP0000789096 ISSN: 0278-0046 * abstract * * page 861 "I. Introduction" * * page 863 "IV. Measurement of Static and Dynamic Characteristics" * * figures 1,2 *</p> <p>---</p>	1,2,5													
A	<p>TUANTRANONT A ET AL: "Smart phase-only micromirror array fabricated by standard CMOS process" PROCEEDINGS IEEE THIRTEENTH ANNUAL INTERNATIONAL CONFERENCE ON MICRO ELECTRO MECHANICAL SYSTEMS, MIYAZAKI, JAPAN, 23-27 JAN. 2000, pages 455-460, XP010377170 ISBN: 0-7803-5273-4 * page 455 "CMOS Micromirror" * * page 457 "Electro-Thermal Analysis" * * figure 2 *</p> <p>-----</p>	1,2,5,9	<p>TECHNICAL FIELDS SEARCHED (Int.Cl.7)</p>												
The present search report has been drawn up for all claims															
2	<p>Place of search MUNICH</p>	<p>Date of completion of the search 30 June 2003</p>	Examiner Besser, V												
<table border="1" style="width: 100%; border-collapse: collapse;"> <thead> <tr> <th style="text-align: left; padding-bottom: 2px;">CATEGORY OF CITED DOCUMENTS</th> <th style="text-align: left; padding-bottom: 2px;">T : theory or principle underlying the invention</th> </tr> </thead> <tbody> <tr> <td style="padding-top: 2px;">X : particularly relevant if taken alone</td> <td style="padding-top: 2px;">E : earlier patent document, but published on, or after the filing date</td> </tr> <tr> <td style="padding-top: 2px;">Y : particularly relevant if combined with another document of the same category</td> <td style="padding-top: 2px;">D : document cited in the application</td> </tr> <tr> <td style="padding-top: 2px;">A : technological background</td> <td style="padding-top: 2px;">L : document cited for other reasons</td> </tr> <tr> <td style="padding-top: 2px;">O : non-written disclosure</td> <td style="padding-top: 2px;">& : member of the same patent family, corresponding document</td> </tr> <tr> <td style="padding-top: 2px;">P : intermediate document</td> <td></td> </tr> </tbody> </table>				CATEGORY OF CITED DOCUMENTS	T : theory or principle underlying the invention	X : particularly relevant if taken alone	E : earlier patent document, but published on, or after the filing date	Y : particularly relevant if combined with another document of the same category	D : document cited in the application	A : technological background	L : document cited for other reasons	O : non-written disclosure	& : member of the same patent family, corresponding document	P : intermediate document	
CATEGORY OF CITED DOCUMENTS	T : theory or principle underlying the invention														
X : particularly relevant if taken alone	E : earlier patent document, but published on, or after the filing date														
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A : technological background	L : document cited for other reasons														
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P : intermediate document															

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**ANNEX TO THE EUROPEAN SEARCH REPORT
ON EUROPEAN PATENT APPLICATION NO.**

EP 02 10 0191

This annex lists the patent family members relating to the patent documents cited in the above-mentioned European search report.
The members are as contained in the European Patent Office EDP file on
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30-06-2003

Patent document cited in search report		Publication date		Patent family member(s)		Publication date
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			JP	2000010029 A	14-01-2000	
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EPO FORM P0459

For more details about this annex : see Official Journal of the European Patent Office, No. 12/82